

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 116792	APPLICATION NO. <u>New U.S. Application</u> 10/696,040		
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT(S) Shimpei MIURA et al.				
		FILING DATE October 2, 2003	GROUP 1045			
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
<i>J</i>	1.	JP A 2002-29701 w/abstract & transl.	1/29/2002	JAPAN	—	—
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
EXAMINER <i>John</i>					DATE CONSIDERED 10-13-06	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

Form PTO-1449 (REV. 1/06)			US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 116792	APPLICATION NO. 10/676,040	
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U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Name		
FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
<i>John</i>	1	DE 102 97 729 T5	07/07/2005	GERMANY	—	—
<i>John</i>	2	DE 31 51 215 A1	12/23/1981	GERMANY	—	—
OTHER DOCUMENTS						
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)				
EXAMINER <i>John</i>					DATE CONSIDERED <i>10-13-06</i>	
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